

<b>Notice of References Cited</b>	Application/Control No. 10/644,999	Applicant(s)/Patent Under Reexamination YOSHIDA, CHIE	
	Examiner Patricia L. Hailey	Art Unit 1755	Page 1 of 1

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*	B	US-6,686,083	02-2004	Saito et al.	429/34
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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